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#### **Key indicators**

Single-crystal X-ray study T = 292 K Mean  $\sigma$ (As–C) = 0.018 Å R factor = 0.047 wR factor = 0.125 Data-to-parameter ratio = 25.3

For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e.

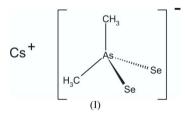
# Caesium dimethyldiselenidoarsenate(V)

The title compound,  $Cs[As(CH_3)_2Se_2]$ , contains discrete tetrahedral dimethyldiselenidoarsenate(V) anions and Cs cations, with As and Cs located on a crystallographic twofold rotation axis. A distorted octahedral coordination is observed for the caesium counter-cation, with Cs···Se distances in the range 3.706 (2)–3.762 (2) Å.

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### Comment

The isolated AsSe<sub>4</sub><sup>3-</sup> anion has been structurally characterized in [Li(NH<sub>3</sub>)<sub>4</sub>]<sub>3</sub>AsSe<sub>4</sub> (Korber & Grothe, 2001), Na<sub>3</sub>As-Se<sub>4</sub>·9H<sub>2</sub>O (Krebs et al., 1990), Rb<sub>3</sub>AsSe<sub>4</sub> and Cs<sub>3</sub>AsSe<sub>4</sub> (Wachhold & Sheldrick, 1996), Rb<sub>3</sub>AsSe<sub>4</sub>·Se<sub>6</sub> and Cs<sub>3</sub>As-Se<sub>4</sub>·2Cs<sub>2</sub>As<sub>2</sub>Se<sub>4</sub>·6Te<sub>4</sub>Se<sub>2</sub> (Wachhold & Sheldrick, 1997), as well as in Ba<sub>2</sub>AsSe<sub>4</sub>(OH)·2H<sub>2</sub>O (Kaub, 1986). In contrast, examples of substituted selenidoarsenate(V) anions are limited to [AsO<sub>3</sub>Se]<sup>3-</sup>, [As(CH<sub>2</sub>CN)Se<sub>3</sub>]<sup>2-</sup> and [AsPh<sub>2</sub>Se<sub>2</sub>]<sup>-</sup>, in respectively Na<sub>3</sub>(AsO<sub>3</sub>Se)·12H<sub>2</sub>O (Krebs et al., 1990), [K(2.2.2crypt]<sub>2</sub>[As(CH<sub>2</sub>CN)Se<sub>3</sub>] (2.2.2-crypt = 4,7,13,16,21,24-hexaoxa-1,10-diazabicyclo[8.8.8]hexacosane; Smith et al., 1998) and  $(pipH_2)(AsPh_2Se_2)$  (pipH = piperidine; Kanda *et al.*, 1998). Methanolothermal conditions (Sheldrick & Wachhold, 1997; Sheldrick & Wachhold, 1998) were employed for the preparation of the alkali metal tetraselenidoarsenates(V) Rb<sub>3</sub>AsSe<sub>4</sub> and Cs<sub>3</sub>AsSe<sub>4</sub> from As<sub>2</sub>Se<sub>3</sub> and Se in the presence of  $M_2CO_3$  (M = Rb, Cs) at 453 K. The unique [As(CH<sub>2</sub>- $(CN)Se_3^{2-}$  anion of  $[K(2.2.2-crypt)]_2[As(CH_2CN)Se_3]$  was obtained by reaction of K, As, Se and (2.2.2-crypt) in NH<sub>3</sub> at 195 K followed by acetonitrile extraction of the solid products and subsequent crystallization. We therefore postulated that it might be possible to isolate analogous methylselenidoarsenates(V) such as  $[As(CH_3)Se_3]^{2-}$  or  $[As(CH_3)_2Se_2]^{-}$  from methanolic selenidoarsenate solutions under oxidizing crystallization conditions.

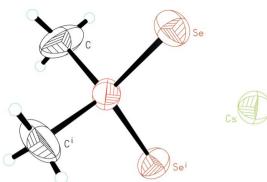


To this end,  $CsAsSe_3 \cdot 0.5H_2O$  (Sheldrick & Kaub, 1986) was dissolved in methanol at 463 K and, following cooling to 293 K, the mother liquor was left to crystallize in air. For the given As:Se ratio of 1:3, the formation of a substituted selenidoarsenate(V) was to be expected.

The  $[As(CH_3)_2Se_2]^-$  anions of the resulting title compound  $Cs[As(CH_3)_2Se_2]$ , (I), display crystallographic twofold rota-

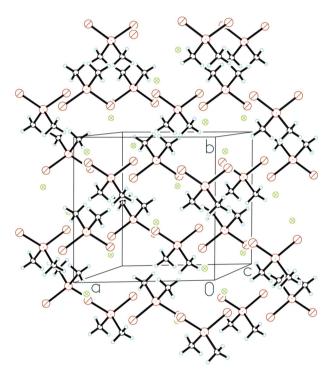
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#### Figure 1

The  $[As(CH_3)_2Se_2]^-$  anion and Cs cation of (I). Displacement ellipsoids are drawn at the 50% probability level. [Symmetry code: (i) -x + 1, y,  $-z + \frac{1}{2}$ .]



#### Figure 2

Projection of the structure of (I) perpendicular to [001]. Atom colour codes: Cs green cross-hatched circles, C black shaded circles, Se orange hatched circles, As red dotted circles, H blue open circles.

tion symmetry with Cs and As located on a twofold rotation axis. The caesium counter-cations are coordinated in a distorted octahedral fashion through six symmetry-related Se atoms (Table 1). A significant shortening is observed for the As—Se bond length [2.262 (2) Å] of (I) in comparison with the tetraselenidoarsenate(V) anions of Rb<sub>3</sub>AsSe<sub>4</sub> and Cs<sub>3</sub>AsSe<sub>4</sub>, for which distances in the range 2.306 (3)– 2.336 (3) Å were reported (Wachhold & Sheldrick, 1996). This marked bond strengthening is in accordance with the increase in the formal bond order from 1.25 in AsSe<sub>4</sub><sup>3-</sup> to 1.5 in [As(CH<sub>3</sub>)<sub>2</sub>Se<sub>2</sub>]<sup>-</sup>. As a result of the partial double-bond character of the participating As—Se bonds, the Se—As—Se angle [117.5 (1)°] is much wider than the C—As—C angle of 106.4 (1)°.

## Experimental

 $CsAsSe_3.0.5H_2O$  (300 mg, 136.1 mmol) (Sheldrick & Kaub, 1986) was heated to 463 K in methanol (0.8 ml) in a sealed glass tube. After cooling to 293 K, the mother liquor was separated from the solid contents and allowed to evaporate slowly in air to afford colourless crystals of (I) in 28% yield.

*Crystal data* Cs<sup>+</sup>·C<sub>2</sub>H<sub>6</sub>AsSe<sub>2</sub><sup>-</sup>

 $M_r = 395.82$ Monoclinic, C2/c a = 9.858 (2) Å b = 10.027 (2) Å c = 9.787 (2) Å  $\beta = 115.92$  (3)° V = 870.1 (3) Å<sup>3</sup> Z = 4

#### Data collection

Siemens P4 four-circle diffractometer  $\omega$  scans Absorption correction:  $\psi$ -scan (XPREP in SHELXTL-Plus; Sheldrick, 1995)  $T_{min} = 0.153$ ,  $T_{max} = 0.275$ 807 measured reflections 759 independent reflections

#### Refinement

Refinement on  $F^2$   $R[F^2 > 2\sigma(F^2)] = 0.047$   $wR(F^2) = 0.125$  S = 1.08759 reflections 30 parameters H-atom parameters constrained

# $$\begin{split} D_x &= 3.022 \text{ Mg m}^{-3} \\ \text{Mo } K\alpha \text{ radiation} \\ \text{Cell parameters from 19} \\ \text{reflections} \\ \theta &= 6.1 - 14.9^{\circ} \\ \mu &= 16.30 \text{ mm}^{-1} \\ T &= 292 \text{ (2) K} \\ \text{Block, colourless} \\ 0.12 \times 0.10 \times 0.08 \text{ mm} \end{split}$$

574 reflections with  $I > 2\sigma(I)$   $R_{int} = 0.047$   $\theta_{max} = 25.0^{\circ}$   $h = 0 \rightarrow 11$   $k = 0 \rightarrow 11$   $l = -11 \rightarrow 10$ 3 standard reflections every 97 reflections intensity decay: none

$w = 1/[\sigma^2(F_o^2) + (0.066P)^2]$
+ 8.7148P]
where $P = (F_0^2 + 2F_c^2)/3$
$(\Delta/\sigma)_{\rm max} < 0.001$
$\Delta \rho_{\rm max} = 1.13 \text{ e} \text{ Å}^{-3}$
$\Delta \rho_{\rm min} = -1.20 \text{ e } \text{\AA}^{-3}$

## Table 1 Selected geometric parameters (

Selected geometric parameters (Å, °).

Cs-Se <sup>i</sup>	3.7063 (17)	Cs-Se <sup>v</sup>	3.7617 (17)
Cs-Se <sup>ii</sup>	3.7063 (17)	As-C <sup>iii</sup>	1.924 (14)
Cs-Se	3.7509 (18)	As-C	1.924 (14)
Cs-Se <sup>iii</sup>	3.7509 (18)	As-Se	2.2621 (15)
Cs-Se <sup>iv</sup>	3.7617 (17)	As-Se <sup>iii</sup>	2.2621 (15)
C <sup>iiii</sup> -As-C	106.4 (12)	C <sup>iiii</sup> -As-Se <sup>iii</sup>	108.4 (5)
C <sup>iiii</sup> -As-Se	107.9 (5)	C-As-Se <sup>iii</sup>	107.9 (5)
C-As-Se	108.4 (5)	Se-As-Se <sup>iii</sup>	117.45 (10)

Symmetry codes: (i)  $x, -y + 1, z - \frac{1}{2}$ ; (ii) -x + 1, -y + 1, -z + 1; (iii)  $-x + 1, y, -z + \frac{1}{2}$ ; (iv)  $-x + \frac{1}{2}, y - \frac{1}{2}, -z + \frac{1}{2}$ ; (v)  $x + \frac{1}{2}, y - \frac{1}{2}, z$ .

The methyl H atoms were refined as riding, with C—H = 0.96 Å and  $U_{iso}(H) = 1.5 U_{eq}(C)$ . The methyl group was allowed to rotate but not to tip. The highest peak in the final difference Fourier synthesis is sited 0.93 Å from As and the deepest hole 0.87 Å from As.

Data collection: *R3m/V* (Siemens, 1989); cell refinement: *R3m/V*; data reduction: *XDISK* (Siemens, 1989); program(s) used to solve structure: *SHELXS97* (Sheldrick, 1997); program(s) used to refine structure: *SHELXL97* (Sheldrick, 1997); molecular graphics: *SHELXTL-Plus* (Sheldrick, 1995); software used to prepare material for publication: *SHELXL97*.

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